



DOCUMENT CHANGE REQUEST

DCR number 722

Changes required for: General

Originator: Denis Lacombe

Date: 2013/02/04

Date sent: 2012/04/27

Organisation: ESTEC

Status: IMPLEMENTED

Title: Microsection Examination Preparation and Evaluation of Capacitors Fixed Ceramic Leaded and

Number: 23400

Issue: 2

Other documents affected:

Page:

10

Paragraph:

6.4

Original wording:

- (a) Any crack in the dielectric which connects any 2 electrodes.
- (b) Any crack in the ceramic which connects an electrode with the surface of the capacitor element or the termination.

Proposed wording:

Any crack in the dielectric

Justification:

Cracks are not acceptable in ceramic capacitor as they may evolve leading to short circuit or open circuit failure. Based on DCR 626 with the agreement of CNES, AVX TPC and Eurofarad.

Attachments:

N/A

Modifications:

N/A

Approval signature:

Date signed:

2013-02-04